

INFORMATION DISCLOSURE
STATEMENT BY APPLICANT

RE-EXAM CONTROL NO.:
APPLICANT: Hollander et al.

(Use several sheets if necessary)
(37 CFR 1.98(b))

FILING DATE:

GROUP:

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
	4,591,256	5-27-86	Matsumura			
	5,258,871	11-02-93	Gupta			
	3,823,313	7/1974	Unema	362	259	
	4,315,150	2/1982	Darringer et al.	374	130	
	4,330,212	5/1982	Miller	356	354	
	4,494,881	1/1985	Everest	374	124	
	4,576,432	3/1986	Ruger	374	124	
	4,582,426	4/1986	Douglas	374	121	
	4,626,686	12/1986	Pompei et al.	374	124	
	4,963,096	10/1990	Khattak et al.	434	121	
	5,085,525	2/1992	Bartosiak et al.	374	124	
	5,172,978	12/1992	Nomura et al.	374	121	
	5,368,392	6/1994	Hollander et al.	374	121	

FOREIGN PATENT DOCUMENTS

DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY OR PATENT OFFICE	CLASS	SUB- CLASS	TRANSLATION	
					YES	NO
GB 2,203,537A	10-19-98	Great Britain				
62-12848	2/1982	Japan	374	121		
57-0255851	2/1982	Japan	374	121		
57-0022521	2/1982	Japan				
32 13 955	10/1982	Germany	374	121		
3607679	11/1986	Germany				

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	Gaylord, Thomas K., Moharam, M. G., 'Analysis and Applications of Optical Diffraction by Gratings,' Proceedings of the IEEE, Vol. 73, No. 5, May 1985, pp. 894-937.
	The Optometrics Group, catalogue Transmission Grating Beamsplitters, 1993, pp. 60-61.
	McCormick, F. B., 'Generation of Large Spot Arrays From a Single Laser Beam by Multiple Imaging with Binary Phase Gratings,' Optical Engineering, April 1989, Vol. 28 No. 4, pp. 299-304.
	Harvey, James E.; Scott, Marion L., 'Hole Grating Beam Sampler-Versatile High-Energy Laser (HEL) Diagnostic Tool,' Optical Engineering, November/December 1981, Vol. 20, No. 6, pp. 881-886.

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	5,524,984	6/1996	Hollander et al.	374	121	
	5,626,424	5/1997	Litvin et al.	374	121	
	5,727,880	3/1998	Hollander et al.	374	121	

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	DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY OR PATENT OFFICE	CLASS	SUB- CLASS	TRANSLATION	
						YES	NO
	0458200	11/1991	European Pat.	374	121		
	0458200A3	11/1993	European Pat.				

OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)

	Haidner, Helmut; Kipfer, Peter; Sheridan, John T.; Schwider, Johannes; Streibl, Norbert; Lindolf, Jürgen; Collischon, Martin; Lang, Anette; Hutfless, Joachim, "Polarizing Reflection Grating Beamsplitter for the 10.6- μ m Wavelength," Optical Engineering, August 1993, Vol. 32, No. 8, pp. 1860-1865.
	Molesini, G.; Pedrini, G.; Quercioli, F., "Laser Unequal Path Interferometer Configurations by Grating Splitting at the Fourier Plane," Optical Engineering, September/October 1984, Vol. 23, No. 5, pp. 646-649.
	Mokry, Patricia A., "Unique Applications of Computer-Generated Diffractive Optical Elements," SPIE Vol. 1052 Holographic Optics: Optically and Computer Generated (1989), pp. 163-171.
	Munnerlyn, C. R., "A Simple Laser Interferometer," Applied Optics, April 1969, Vol. 8, No. 4, pp. 827-829.
	Miller, Miroslav, "Photoresist as a Recording Material for Holographic Elements," SPIE vol. 2108, 8 pp.
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	Kim, Richard C.; Case, Steven K., "Holographic Beamsplitter for Multiple Plane Wave Formation with Matched Phasefronts," SPIE (1989) Vol. 1052, pp. 52-64.
	Shuying, Wang; Chun, Lei, "New Method of Designing High-Efficiency Multi-Beam Light-Splitter," SPIE Vol. 1973, pp. 87-93.
	Lu, Xuenong; Wang, Ying; Wu, Minxian; Jin, Guofan, "The Fabrication of a 25x25 Multiple Beam Splitter," Vol. 72, number 3.4, pp. 157-162.

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							YES	NO

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		Azzam, R. M. A.; Forgala, G. W., "Creation of an Optical XYZ Coordinate System Using Bidirectional Blazing From A Symmetric Triangular-Groove Grating In a Conical Diffraction Mount," Optics Letters, Vol. 18, No. 24, 15 Dec. 1993, pp. 2162-2164, USA.
		Hong, Baojin; He, Yongrong; Ye, Ronghua, "Laser Grating Interferometer Using Grating as Beam Splitter," Zhongguo Jiguang/Chinese Journal of Lasers, vol. A20, No. 1, 1993, pp. 34-37, China.
		Kawatsuki, N.; Uetsuki, M., "Crossed Grating Beam Splitter for Magneto-optical Pickup Head," Japanese Journal of Applied Physics Part 1 - Regular Papers Short Notes & Review Papers, Vol. 29, No. 11, Nov. 1990, pp. 2420-2423, Japan.
		Lehureau, J. C.; Beguin, J. Y.; Colineau, J., "Polarizing Grating Beamsplitter Using a Liquid Crystal Cell," Japanese Journal of Applied Physics, Supplement, Vol. 28, Suppl. 28-3, 1989, pp. 201-203, Japan.
		Hansen, J. P.; Strong, J., "Performance of a Simple Spherical Lamellar Grating Beamsplitter by Wavefront Division," Aspen International Conference on Fourier Spectroscopy, Air Force Cambridge Res. Labs. 1971, pp. 215-220, Bedford, MA.
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		Courjon, D; Bulabojs, J., "Noncoherent Microholography Using a Holographic Optical Element As A Beamsplitter," Optical Engineering, Vol. 20, No. 2, March-April 1981, pp. 233-235, USA.
		Spornik, N. M.; Tuev, A. F., "Universal Interferometer with the Reference Wave Formed From the Object Wave," Optiko-Mekhanicheskaya Promyshlennost, Vol. 59, No. 9, Sept. 1992, pp. 53-56, Russia.
		Mikes, T., "Fringe Benefits: Applications of Holographic Elements," Photonics Spectra, Vol. 17, No. 3, March 1983, pp. 40-44, USA.

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[illegible]

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[illegible]

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		"Laser Sighting for Precise Noncontact Temperature Measurement", Raytek, Santa Cruz, Calif (8 Nov. 1993)

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